Se	arch	rch Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
10/781,665	LEE, JONG PYO	LEE, JONG PYO	
Examiner	Art Unit		
HUYEN D. LE	2615		

SEARCHED			
Class	Subclass	Date	Examiner
381	398, 430, 432, 423, 424-428	8/17/2007	HL
181	167	8/17/2007	HL
· 381	169	8/17/2007	HL
381	170	8/17/2007	HL
381	171	8/17/2007	HL
381	172	8/17/2007	HL
29	594	8/17/2007	HL
29	609.1	8/17/2007	HL
84	171	8/17/2007	HL
442	120	8/17/2007	HL
442	394	8/17/2007	HL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
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